

REVISION HISTORY

Rev. 1.12

RevisionDescriptionIssue DateRev. 1.12Initial IssueMay 15, 2012

AS6C4008A

512K X 8 BIT LOW POWER CMOS SRAM

FEATURES

 Fast access time: 55ns
 Low power consumption: Operating current: 30mA (TYP.)

Standby current : 1µA (TYP.) SL-version

■ Single 2.7V ~ 3.6V power supply

■ All inputs and outputs TTL compatible

■ Fully static operation

■ Tri-state output

■ Data retention voltage : 1.5V (MIN.)

■ Green package available

■ Package: 32-pin 450 mil SOP

32-pin 8mm x 20mm TSOP-I 32-pin 8mm x 13.4mm STSOP 36-ball 6mm x 8mm TFBGA 32-pin 600 mil P-DIP

32-pin 600 mil P-DIP 32-pin 400 mil TSOP-II

GENERAL DESCRIPTION

The AS6C4008A is a 4,194,304-bit low power CMOS static random access memory organized as 524,288 words by 8 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

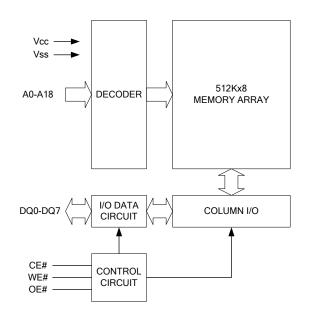
The AS6C4008A is well designed for very low power system applications, and particularly well suited for battery back-up nonvolatile memory application.

The AS6C4008A operates from a single power supply of $2.7V \sim 3.6V$ and all inputs and outputs are fully TTL compatible

PRODUCT FAMILY

Product	Operating	Van Bango	Spood	Power D	issipation
Family	Temperature	Vcc Range	Speed	Standby(IsB1,TYP.)	Operating(Icc,TYP.)
AS6C4008A	-40 ~ 85°C	2.7 ~ 3.6V	55ns	1μA(SL)	30mA

FUNCTIONAL BLOCK DIAGRAM



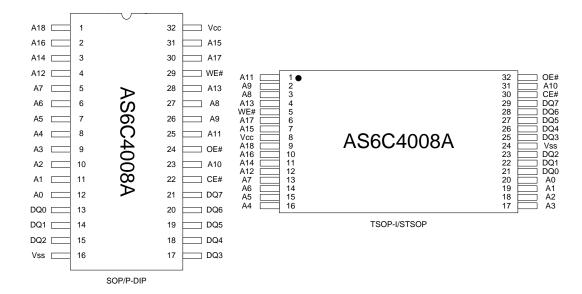
PIN DESCRIPTION

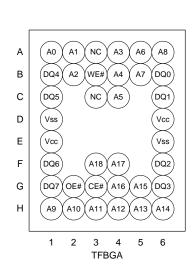
SYMBOL	DESCRIPTION
A0 - A18	Address Inputs
DQ0 – DQ7	Data Inputs/Outputs
CE#	Chip Enable Inputs
WE#	Write Enable Input
OE#	Output Enable Input
Vcc	Power Supply
Vss	Ground
NC	No Connection

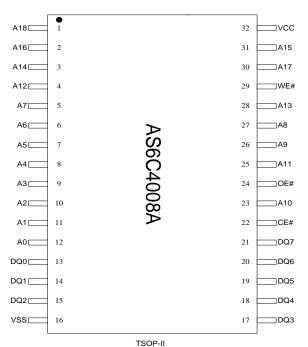
PIN CONFIGURATION



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ABSOLUTE MAXIMUN RATINGS*

PARAMETER	SYMBOL	RATING	UNIT
Voltage on Vcc relative to Vss	VT1	-0.5 to 4.6	V
Voltage on any other pin relative to Vss	VT2	-0.5 to Vcc+0.5	V
Operating Temperature	Та	-40 to 85(I grade)	$^{\circ}\!\mathbb{C}$
Storage Temperature	Тѕтс	-65 to 150	$^{\circ}\mathbb{C}$
Power Dissipation	PD	1	W
DC Output Current	Іоит	50	mA

^{*}Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.

TRUTH TABLE

MODE	CE#	OE#	WE#	I/O OPERATION	SUPPLY CURRENT
Standby	Н	Х	Х	High-Z	ISB,ISB1
Output Disable	L	Н	Н	High-Z	Icc,Icc1
Read	L	L	Н	Dout	Icc,Icc ₁
Write	L	Х	L	Din	lcc,lcc1

Note: $H = V_{IH}$, $L = V_{IL}$, X = Don't care.



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DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	ON		MIN.	TYP. ^{^4}	MAX.	UNIT
Supply Voltage	Vcc				2.7	3.0	3.6	V
Input High Voltage	V _{IH} ^{*1}				2.2	-	Vcc+0.3	V
Input Low Voltage	V _{IL} ²				- 0.2	-	0.6	V
Input Leakage Current	ILI	$V_{CC} \ge V_{IN} \ge V_{SS}$			- 1	-	1	μΑ
Output Leakage Current	ILO	Vcc ≧ Vo∪т ≧ Vss, Output Disabled			- 1	-	1	μA
Output High Voltage	Vон	Iон = -1mA			2.2	2.7	-	V
Output Low Voltage	Vol	I _{OL} = 2mA			-	-	0.4	V
Average Operating	Icc	Cycle time = Min. CE# = V _{IL} and I _{I/O} = 0mA Other pins at V _{IL} or V _I +	1	- 55	1	30	40	mA
Power supply Current	Icc1	Cycle time = 1µs CE#≦0.2V and I _{VO} = 0mA Other pins at 0.2V or Vcc-0.2		V	1	4	5	mA
	IsB	CE# = VIH or CE2 = VII other pins at VIL or VIH	CE# = VIH or CE2 = VIL, other pins at VIL or VIH		-	0.3	1.25	mA
Standby Power Supply Current		CE# >\/aa 0 2\/	SLI ^{*5}	25 ℃	-	1	3	μA
	I _{SB1}	Others at 0.2V or Vcc - 0.2V		40°C		1	3	μA
			SLI		-	1	12	μΑ

Notes:

- 1. VIH(max) = VCC + 3.0V for pulse width less than 10ns.
- 2. V_{IL}(min) = Vss 3.0V for pulse width less than 10ns.
- 3. Over/Undershoot specifications are characterized, not 100% tested.
- 4. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at Vcc = Vcc(TYP.) and T_A = 25°C
- 5. This parameter is measured at Vcc = 3.0V

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CAPACITANCE (TA = 25°C, f = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	6	pF
Input/Output Capacitance	C _{I/O}	-	8	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

Input Pulse Levels	0.2V to Vcc - 0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	1.5V
Output Load	$C_L = 30pF + 1TTL$, $I_{OH}/I_{OL} = -1mA/2mA$

AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

PARAMETER	SYM.	AS6C4008A-55		UNIT
		MIN.	MAX.	
Read Cycle Time	trc	55	-	ns
Address Access Time	taa	-	55	ns
Chip Enable Access Time	tACE	-	55	ns
Output Enable Access Time	toe	-	30	ns
Chip Enable to Output in Low-Z	tclz*	10	-	ns
Output Enable to Output in Low-Z	toLz*	5	-	ns
Chip Disable to Output in High-Z	tcHz*	-	20	ns
Output Disable to Output in High-Z	tonz*	-	20	ns
Output Hold from Address Change	tон	10	-	ns

(2) WRITE CYCLE

PARAMETER	SYM.	AS6C4008A-55		UNIT
		MIN.	MAX.	
Write Cycle Time	twc	55	-	ns
Address Valid to End of Write	taw	50	-	ns
Chip Enable to End of Write	tcw	50	-	ns
Address Set-up Time	tas	0	-	ns
Write Pulse Width	twp	45	-	ns
Write Recovery Time	twr	0	-	ns
Data to Write Time Overlap	tow	25	-	ns
Data Hold from End of Write Time	tон	0	-	ns
Output Active from End of Write	tow*	5	-	ns
Write to Output in High-Z	twnz*	-	20	ns

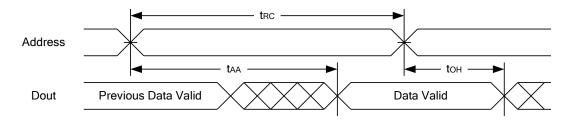
^{*}These parameters are guaranteed by device characterization, but not production tested.

Alliance Memory, Inc. 551 Taylor Way, Suite #1, San Carlos, CA 94070 Phone: 650-610-6800

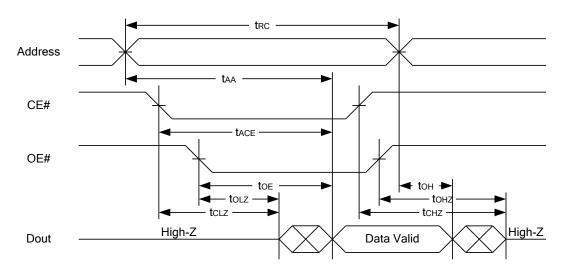


TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)



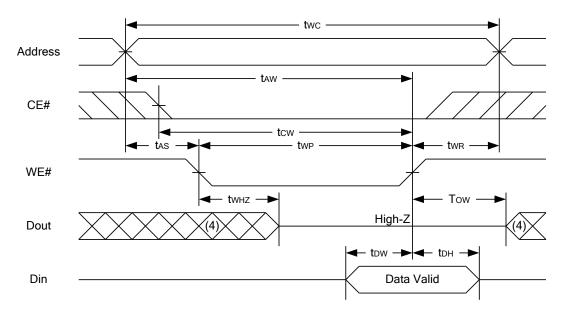
READ CYCLE 2 (CE# and OE# Controlled) (1,3,4,5)



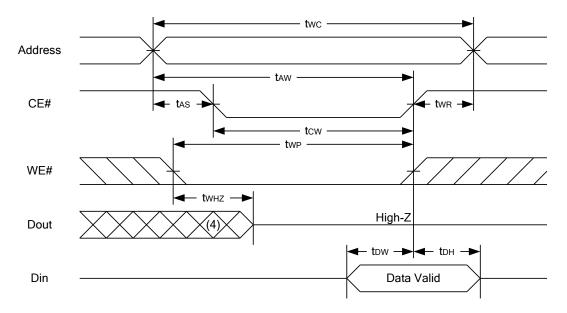
Notes

- 1.WE# is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low.
- 3.Address must be valid prior to or coincident with CE# = low,; otherwise tAA is the limiting parameter.
- 4.tclz, tolz, tchz and tohz are specified with CL = 5pF. Transition is measured ±500mV from steady state.
- $5. At any given temperature \ and \ voltage \ condition, \ tchz \ is \ less \ than \ tclz \ , \ tohz \ is \ less \ than \ tolz.$

WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



WRITE CYCLE 2 (CE# Controlled) (1,2,5,6)



Notes

- 1.WE#, CE# must be high during all address transitions.
- 2.A write occurs during the overlap of a low CE#, low WE#.
- 3.During a WE# controlled write cycle with OE# low, twp must be greater than twHz + tpw to allow the drivers to turn off and data to be placed on the bus.
- $\dot{\text{4.During}}$ this period, I/O pins are in the output state, and input signals must not be applied.
- 5.If the CE# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
- 6.tow and twHz are specified with CL = 5pF. Transition is measured $\pm 500mV$ from steady state.



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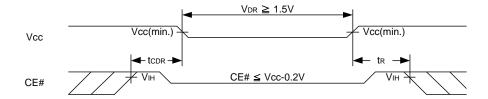
DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT	
Vcc for Data Retention	V_{DR}	CE# ≧ V _{CC} - 0.2V		1.5	ı	3.6	V	
		Vcc = 1.5V	SLI	25 ℃	-	0.5	2.5	μΑ
Data Retention Current	Inn	$CE# > V_{00} = 0.2V$	_	40 ℃	-	0.5	2.5	μΑ
		Other pins at 0.2V or Vcc-0.2V	SLI		-	0.5	10	μΑ
Chip Disable to Data Retention Time	ICDD	See Data Retention Waveforms (below)			0	-	-	ns
Recovery Time	t _R				tRC∗	-	-	ns

tRC* = Read Cycle Time

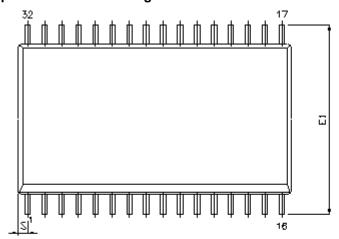
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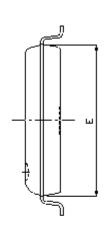
DATA RETENTION WAVEFORM

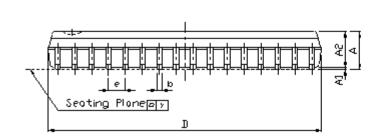


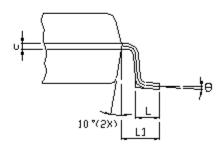
PACKAGE OUTLINE DIMENSION

32 pin 450 mil SOP Package Outline Dimension







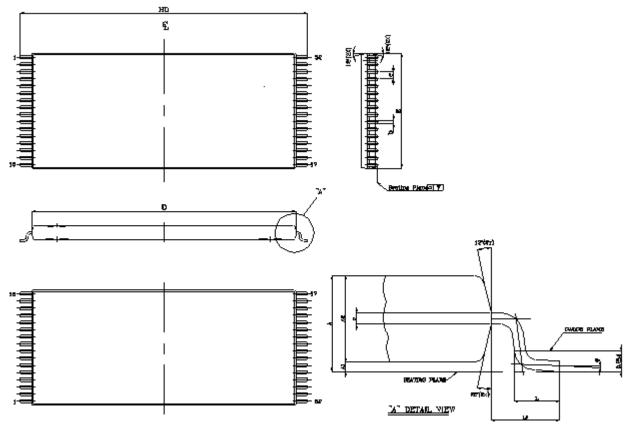


UNIT SYM.	INCH.(BASE)	MM(REF)
А	0.120(MAX)	3.048(MAX)
A1	0.004(MIN)	0.102(MIN)
A2	0.116(MAX)	2.946(MAX)
b	0.016(TYP)	0.406(TYP)
С	0.008(TYP)	0.203(TYP)
D	0.817(MAX)	20.75(MAX)
E	0.445±0.006	11.303±0.152
E1	0.555±0.025	14.097±0.635
е	0.050(TYP)	1.270(TYP)
L	0.033±0.017	0.838±0.432
L1	0.055±0.008	1.397±0.203
S	0.026(MAX)	0.660(MAX)
у	0.004(MAX)	0.101(MAX)
Θ	0° -10°	0° -10°





32 pin 8mm x 20mm TSOP-I Package Outline Dimension

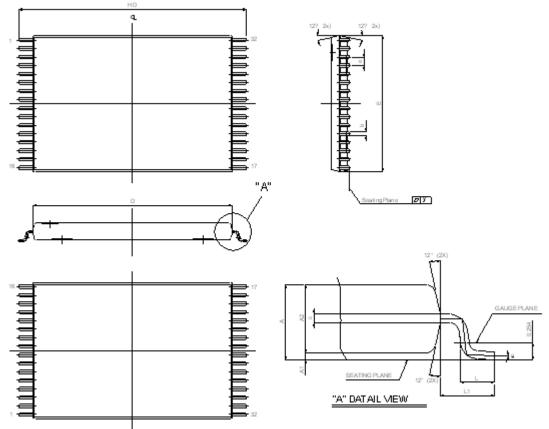


SYM. UNIT	INCH(BASE)	MM(REF)
Α	0.047 (MAX)	1.20 (MAX)
A1	0.004 ±0.002	0.10 ±0.05
A2	0.039 ±0.002	1.00 ±0.05
b	0.009 ±0.002	0.22 ±0.05
С	0.006 ±0.002	0.155 ±0.055
D	0.724 ±0.008	18.40 ±0.20
Е	0.315 ±0.008	8.00 ±0.20
е	0.020 (TYP)	0.50 (TYP)
HD	0.787 ±0.008	20.00 ±0.20
L	0.024 ±0.004	0.60 ±0.10
L1	0.0315 ±0.004	0.08 ±0.10
У	0.003 (MAX)	0.08 (MAX)
Θ	0°∼5°	0°∼5°





32 pin 8mm x 13.4mm STSOP Package Outline Dimension



SYM. UNIT	INCH(BASE)	MM(REF)
А	0.049 (MAX)	1.25 (MAX)
A1	0.004 ±0.002	0.10 ±0.05
A2	0.039 ±0.002	1.00 ±0.05
b	0.009 ±0.002	0.22 ±0.05
С	0.006 ±0.002	0.155 ±0.055
D	0.465 ±0.008	11.80 ±0.20
E	0.315 ±0.008	8.00 ±0.20
е	0.020 (TYP)	0.50 (TYP)
HD	0.528±0.008	13.40 ±0.20.
L	0.02 ±0.008	0.50 ±0.20
L1	0.031 ±0.005	0.8 ±0.125
у	0.003 (MAX)	0.076 (MAX)
Θ	0°∼5°	0°∼5°

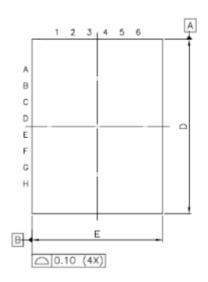
AS6C4008A

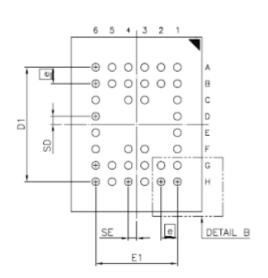
512K X 8 BIT LOW POWER CMOS SRAM

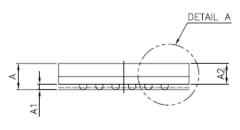
36 ball 6mm × 8mm TFBGA Package Outline Dimension

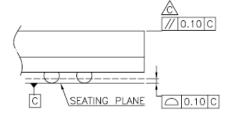
TOP VIEW

BOTTOM VIEW



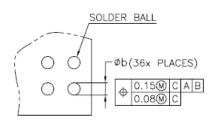






SIDE VIEW

DETAIL A



CVII	DIMENSION (mm)			DIMENSION (inch)		
STM.	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.
Α	—	_	1.20		_	0.047
A1	0.20	0.25	0.30	0.008	0.010	0.012
A2	—	_	0.94	_	_	0.037
b	0.30	0.35	0.40	0.012	0.014	0.016
D	7.95	8.00	8.05	0.313	0.315	0.317
D1	5.25 BSC			0.207 BSC		
E	5.95	6.00	6.05	0.234	0.236	0.238
E1	3.75 BSC 0.375 TYP 0.375 TYP			0.148 BSC		
SE				0.015 TYP		
SD				0.015 TYP		
е	0.75 BSC			0.030 BSC		
	A1 A2 b D D1 E E1 SE SD	SYM. MIN. A — A1 0.20 A2 — b 0.30 D 7.95 D1 5 E 5.95 E1 3 SE 0 SD 0	SYM. (mm) MIN. NOM. A — — A1 0.20 0.25 A2 — — b 0.30 0.35 D 7.95 8.00 D1 5.25 BSC E 5.95 6.00 E1 3.75 BSC SE 0.375 TY SD 0.375 TY	SYM.	SYM. (mm) MIN. NOM. MAX. MIN. A — — 1.20 — A1 0.20 0.25 0.30 0.008 A2 — — 0.94 — b 0.30 0.35 0.40 0.012 D 7.95 8.00 8.05 0.313 D1 5.25 BSC 0 E 5.95 6.00 6.05 0.234 E1 3.75 BSC 0 SE 0.375 TYP 0 SD 0.375 TYP 0	(mm) (inch) SYM. (mm) (inch) MIN. NOM. MAX. MIN. NOM. A — — 1.20 — — A1 0.20 0.25 0.30 0.008 0.010 A2 — — 0.94 — — b 0.30 0.35 0.40 0.012 0.014 D 7.95 8.00 8.05 0.313 0.315 D1 5.25 BSC 0.207 BS E 5.95 6.00 6.05 0.234 0.236 E1 3.75 BSC 0.015 TY SD 0.375 TYP 0.015 TY

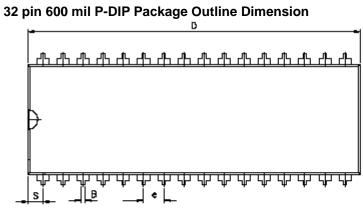
DETAIL B

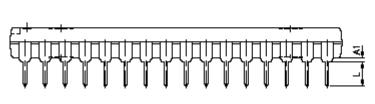
NOTE:

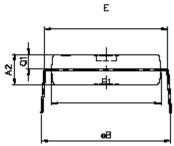
CONTROLLING DIMENSION: MILLIMETER.
 REFERENCE DOCUMENT: JEDEC MO-207.











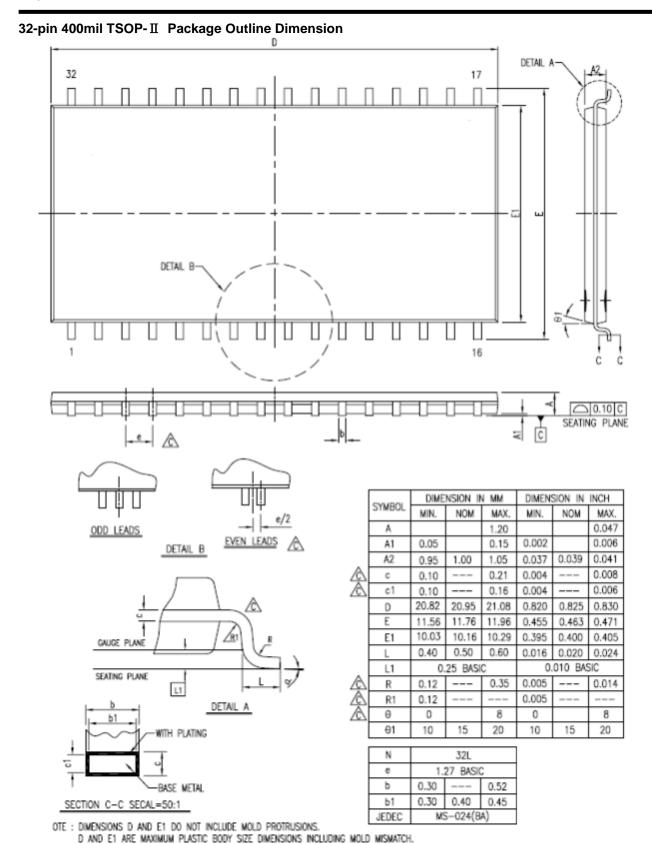
SYM. UNIT	INCH(BASE)	MM(REF)	
A1	0.015(MIN)	0.381(MIN)	
A2	0.155±0.005	3.937±0.127	
В	0.018±0.005	0.457±0.127	
D	1.650±0.01	41.910±0.254	
E	0.600±0.010	15.240±0.254	
E1	0.545±0.005	13.843±0.127	
е	0.100(TYP)	2.540(TYP)	
eB	0.650±0.020	16.510±0.508.	
Ĺ	0.158±0.043	4.013±1.092	
S	0.075±0.010	1.905±0.254	
Q1 0.070±0.005		1.778±0.127	

Note: D/E1/S dimension do not include mold flash.





512K X 8 BIT LOW POWER CMOS SRAM



Alliance Memory, Inc. 551 Taylor Way, Suite #1, San Carlos, CA 94070 Phone: 650-610-6800



ORDERING INFORMATION

Alliance	Organization	vcc	Package	Operating Temp	Speed ns
AS6C4008A-55PCN	512k x 8	3V	32pin 600mil DIP	Commercial - 0°C to 70°C	55
AS6C4008A-55SIN	512k x 8	3V	32pin 450mil SOP	Industrial - -40°C to 85°C	55
AS6C4008A-55TIN	512k x 8	3V	32pin TSOP 1 (8 x 20 mm)	Industrial - -40°C to 85°C	55
AS6C4008A-55STIN	512k x 8	3V	32pin sTSOP (8 x 13.4 mm)	Industrial - -40°C to 85°C	55
AS6C4008A-55BIN	512k x 8	3V	36pin TFBGA (6mm x 8mm)	Industrial - -40°C to 85°C	55
AS6C4008A-55ZIN	512k x 8	3V	32pin 400mil TSOP 11	Industrial - -40°C to 85°C	55

PART NUMBERING SYSTEM

AS6C	4008	-55	Х	X	N
Low power SRAM prefix	Device Number 40 = 4M 08 = by 8	Access Time	Package Options: P = 32 pin 600 mil P-DIP S = 32 pin 450 mil SOP T = 32 pin TSOP 1 (8mm x 20mm) Z = 32 pin 400 mil TSOP 11 ST = 32 pin sTSOP (8mm x 13.4mm) B = 36 pin TFBGA (6mm x 8mm)	Temperature Range: C = Commercial (0°C to +70°C) I = Industrial (-40°C to +85°C)	N = Lead Free ROHS Compliant Part